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81563 (6653)

Amendment to the Claims:

1 (original): A method of screening defects comprising steps of:

(a) measuring a quiescent current at a first supply voltage for each of a plurality of devices;

(b) measuring a quiescent current at a second supply voltage for each of the plurality of devices;

(c) generating a plot of the quiescent current measured at the first supply voltage vs. the quiescent current measured at the second supply voltage for each of the plurality of devices;

(d) determining a range of intrinsic variation of quiescent current in the plot; and

(e) identifying any of the plurality of devices corresponding to a measurement plotted outside the range of intrinsic variation as defective.

2 (original): The method of Claim 1 wherein the second supply voltage has a value selected so that quiescent current of substantially all of the plurality of devices is within the range of intrinsic variation.

3 (original): The method of Claim 1 wherein the first supply voltage is a nominal supply voltage of the plurality of devices.

4 (original): The method of Claim 1 wherein the second supply voltage has a value selected in a sub-threshold voltage region of the plurality of devices.

5 (original): The method of Claim 1 wherein the

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quiescent current is measured at the first supply voltage or the second supply voltage for multiple stop points in a test pattern.

6 (original): The method of Claim 1 wherein the quiescent current is measured at the second supply voltage for only one stop point in a test pattern.

7 (original): A computer program product for screening defects comprising:

a medium for embodying a computer program for input to a computer; and

a computer program embodied in the medium for causing the computer to perform steps of:

(a) measuring a quiescent current at a first supply voltage for each of a plurality of devices;

(b) measuring a quiescent current at a second supply voltage for each of the plurality of devices;

(c) generating a plot of the quiescent current measured at the first supply voltage vs. the quiescent current measured at the second supply voltage for each of the plurality of devices;

(d) determining a range of intrinsic variation of quiescent current in the plot; and

(e) identifying any of the plurality of devices corresponding to a measurement plotted outside the range of intrinsic variation as defective.

8 (original): The computer program product of Claim 7 wherein the second supply voltage has a value selected so that quiescent current of substantially all of the plurality of devices is within the range of intrinsic variation.

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9 (original): The computer program product of Claim 7 wherein the first supply voltage is a nominal supply voltage of the plurality of devices.

10 (original): The computer program product of Claim 7 wherein the second supply voltage has a value selected in a sub-threshold voltage region of the plurality of devices.

11 (original): The computer program product of Claim 7 wherein the quiescent current is measured at the first supply voltage or the second supply voltage for multiple stop points in a test pattern.

12 (original): The method of Claim 1 wherein the quiescent current is measured at the second supply voltage for only one stop point in a test pattern.

13 (new): The method of Claim 2 wherein the first supply voltage is a nominal supply voltage of the plurality of devices.

14 (new): The method of Claim 2 wherein the quiescent current is measured at the first supply voltage or the second supply voltage for multiple stop points in a test pattern.

15 (new): The computer program product of Claim 8 wherein the first supply voltage is a nominal supply voltage of the plurality of devices.

16 (new): The computer program product of Claim 8 wherein the quiescent current is measured at the first supply

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voltage or the second supply voltage for multiple stop points
in a test pattern.